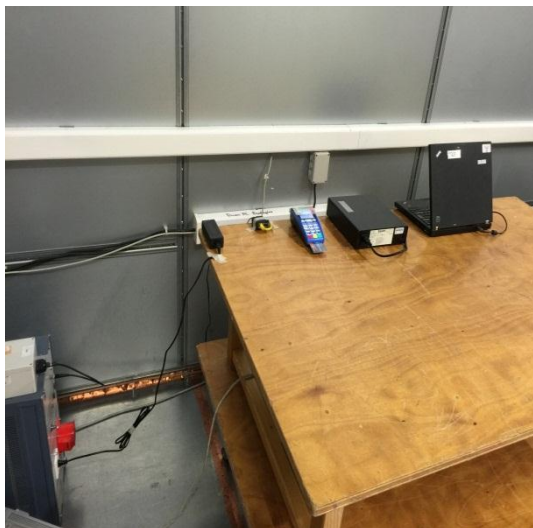


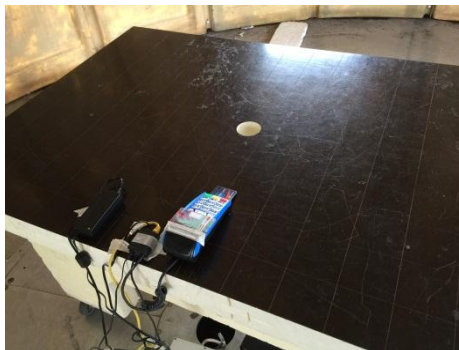
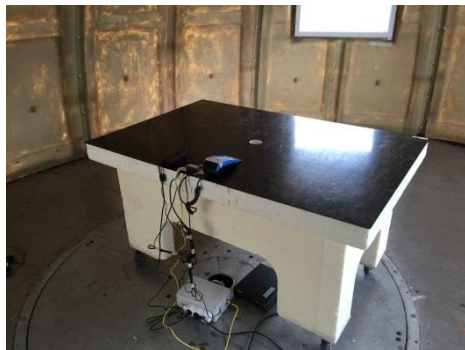
CONDUCTED AND RADIATED MEASUREMENT PHOTO

FCCID: XKB-ICT250V3
IC: 2586D-ICT250CLV3

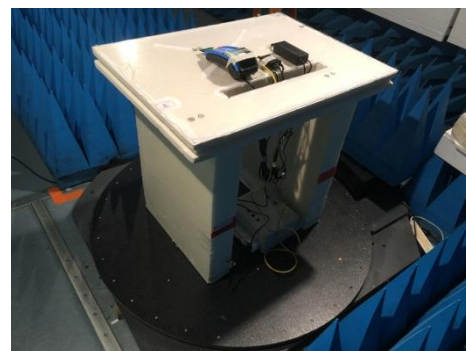
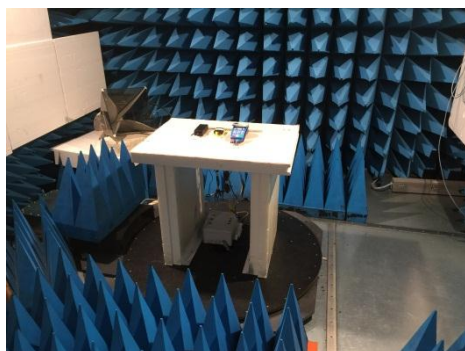
1.1 Conducted emission



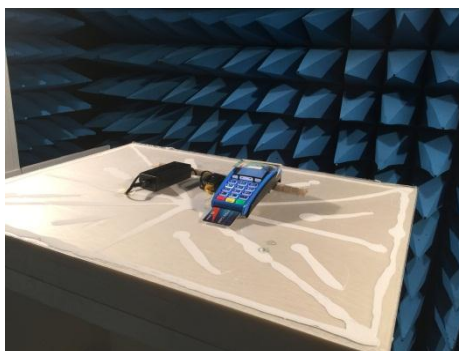
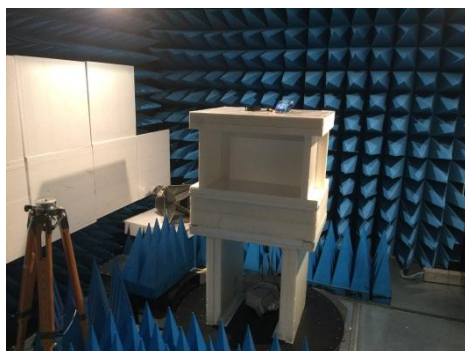
1.2 Radiated emissions



Test setup on OATS



Test setup in anechoic chamber (9kHz to 1GHz)



Test setup in anechoic chamber (1GHz to 2GHz)